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TABLE OF CONTENTS

STAMP: Statistical Trojan Attribution via Multiclass Power-Trace Analysis 1
Sinthanai Selvi. G, Senthilkumar Dhamodharan, Karthika R, Abirami Vinayagamoorthy

Polynomial Regression Based Qualitative Assessment of Automated Test Equipment Calibration 7
Anand Venkatachalam, Ernst Aderholz, Matthias Sauer, Simon Schweizer, Matthias Werner, Ilia Polian

Design and Context Aware Embedded Monitor Analytics Through High-Volume Algorithmics and Explainable AI 13
Dan Alexandrescu, Shubharthi Datta, Leela Krishna Thota

Unified Compact Health and Aging Models for Manufacturing to In-Field Silicon Quality and Reliability Management 19
Dan Alexandrescu, Shubharthi Datta, Leela Krishna Thota

Real-Time Path Resistance Compensation and Spatial Diagnostics for High-Volume Wafer Test 25
Sujith Thomas, Siva Elango S, Dinesh Sharma, Mathangi Raghuraman

Enabling Flow Automation for HBM Testing Using A Plug-n-Play DFT Interface 31
Quoc Phan, Anshuman Chandra, Bartosz Żelek, Barbara Działowska, Marta Stępniewska Jonathan Gaudet

Towards Secure IoT: A Lightweight PUF-Based Proximity-Aware Authentication Protocol for Resource-Constrained IoT Devices 37
Abdulla Syed, Navya Sri Tulluru, Mounika Mellamarthi

RL-Driven 3D Clustering of Jscan Architecture with Routing and Area Optimization in Chiplet Sip 43
Hilay Patel, Naman Kalra, Jaynarayan T. Tudu

Constraint-Based Functional Testing of Encrypted Memory Systems Using Magic Square Patterns 49
C.P. Ravikumar

DFT-Enhanced Spare Cell Architecture for Scan-Integrated ECO and Leakage Optimization in SoCs 55
Pramod Gayakwad, Raghavendra H. D, Chandramohan K. P, Khushboo Rathore, Vishwanath Kunchigi Vamsi Krishna Oliveti, Santhosh Kamatam

Reliability Refining Next Generation UV Cured Conformal Coatings Under Harsh Environment Testing 61
Aurkie Ray, Cole Sandvold, Andi Duffy, Bethany Turner, Saskia Hogan, Phil Kinner, Christopher Allen Anna Lifton

A Methodology for Robust Testing of Through Glass Vias (TGV) on Glass Substrate-Based 3D Chiplets 67
Manisha Kumari, Jaynarayan T Tudu, Binod Kumar

Exploring Differential Evolution Algorithm with Fitness-and Position-Based Selection in Search of Best Test Pattern for Combinational ATPG 73
Manish Kumar, Isha Dubey, Priyajit Bhattacharya, Rahul Bhattacharya

Test Pattern-Driven Detection of Hardware Trojans Using Switching Activity Analysis in FPGA-Based Systems 79
Kannan S J, Chinakaku Lakshmi Prasanna, Sobhit Saxena

A Novel Verification Method for Debug Tracing-in Close Chassis System 85
Maneesh Pandey, Madhav Lekkala

Assertion-Centric UVM Verification of a Fault-Injectable 32-Bit RISC-V ALU-IFU Subsystem 90
Divyanshi Sharma, Sandeep Patel

Rethinking RTL DFT: A Discrete RTL Flow for Parallel DFT Integration 96
Mohan Raj Gopal, Veejaye Panayadian, Kundan Jha

State-Isolated Scan - a Secure Low-Power Scan Architecture 102
C.P. Ravikumar, Kushal C.

eFPGA-Enabled Dynamic Access Control for Secure IEEE 1687 (IJTAG) Networks 108
Anekait Thampi, Anshul Raghavendra Katti, Manish Nagaraju, Sudeendra Kumar K

Physical Design Aware Verification Methodology for Closing Coverage Gaps in Sharedbus MBIST 114
Shivam Tulsyan, Mayank Parasrampuria, Vasudevan Pillai A, Prachi Sinha, Maheedhar Jalasutram

Assertion Based Formal Verification of AES 128 Crypto Core 120
Shivang Sharma, Vineeth Jaisal, Prashant Singh

AI-Driven IP Configuration Optimization for Post-Silicon Validation 126
Akhilesh Tiwary, Nihar Chaniyara, Utsav Banerjee, Maneesh Kumar Pandey

A Novel Power-Aware ATPG with Biaxial Transition Control for Extreme Low Power Targets 132
Hanumant Tuntoni, Hillol Maity, Sreenu Kakunuri, Peter Wohl, Parthajit Bhattacharya, Bruce Xue Geguang Miao

Physically Aware Weighted Fault Model: a New Paradigm in Testing 138
Sandipan Sharma, Srinivas Vooka, Maheedhar Jalasutram, Pranav Murthy, Chieh-Jen Jeren Ku Yanhan Zhu

Innovative Memory Interconnect Architecture: Setting New Standards for Security, Safety and Performance in Real-Time Control MCUs 144
Prasanth Viswanathan Pillai, Varshashree Kottadamane, Saya Goud Langadi, Labeeb K, Naveen Kothuri Narendra Ravilla, Ramakrishna Pidaparthi, Rohit Chaudhari, Sivareddy Maramreddy

T-Map: a Cross-Platform Ai Driven Test-Program Metadata Analysis Tool for Digital Coverage, Force, Limit and Range Verification 150
Kaushik Chakravorty, Dundapa Sankapal, Vishal Rohilla, Sudhish Raj GJ, Pratyush Dargan, Robert Cook

Enhancements in Memory Test for Improved Diagnosability and Comprehensive Multi-Bank Test 156
Prachi Sinha, Veerabhadra Rao Vasa, Shivam Tulsyan, Mayank Parasrampuria

Cost Aware Sector Symmetry and Wafer Cutting Methods for 3D ICs with Heterogeneous Defects 161
Tanusree Kaibartta, Saksham Jha, Digvijay Anand, Debesh K Das

Design of a Sat-Resilient IJTAG Architecture for Secure and Scalable on-Chip Instrument Access 167
Saravanan P, Dharani Sree K, Jothika K, Nivashini S, Sivaprabha Sri PL

PQC-Based Secure Access Manager for IJTAG Network 173
Prajwal G S Basavaraj, Abhinav S, Arun Kumar N, Sudeendra Kumar K

A Unified Fault Detection and Repair Framework for Memristor-Based Non-Volatile Memories 179
Aryan Anand, Vishal Gupta

A Novel Hardware Design for Effective Supply Voltage Glitch Injection 185
Asmita Mohapatra, Ashok Kumar, Antony Varghese

Comprehensive Coverage Framework for LPDDR6 Feature Validation: Navigating Complex Modes and Reducing the Verification Closure Gap 191
Shyam Sharma, Dharini Subhashchandran, Gruhesh Patel, Meghna Ahuja

Validation Methodology to Characterize Absolute Propagation Delay, Delay Variation Over Temperature and Programmable Delay of 1ps DNL Step in Wideband Rf Buffers Upto 12.8Ghz 197
Harish Kumar Ramesh, Jason Xavier, Pranav Kumar

Signal Integrity Simulation Time Optimization: A Novel AI Framework Using Minute Scale SI Predictor in High Speed Test Interface Hardware Design 203
Senthilkumar Dhamodharan, Lokapriya B, Dyaneswaran A, Karthika R, Lokendran S

A Novel Plug-in Module Architecture for Extending Automatic Test Equipment Capability to Wireless Testing of Pin-Less Semiconductor Devices 209
Manoj Pachaiyan, Senthilkumar Dhamodharan, Sathiyapriya Krishnamoorthy

A Hybrid Data-Driven Framework for Post-Silicon Validation of Neuromorphic Integrated Circuits 215
Kalyana Sundaram Chandran, Senthilkumar Dhamodharan, Sindhu Mathy S